



Optical MEMS for QIP applications

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2/23/2006



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Outline

- Sandia MEMS technology –SUMMiT V
- Layout of current mirror array/mirror structure
- Mirror performance
 - Static
 - Dynamic
 - Optical (Mirror Figure)
 - ZEMAX model of effect of mirror figure on system performance
- Some improved switching speed results
- Mirrors for QIP
- Conclusion





Optical MEMS at Sandia

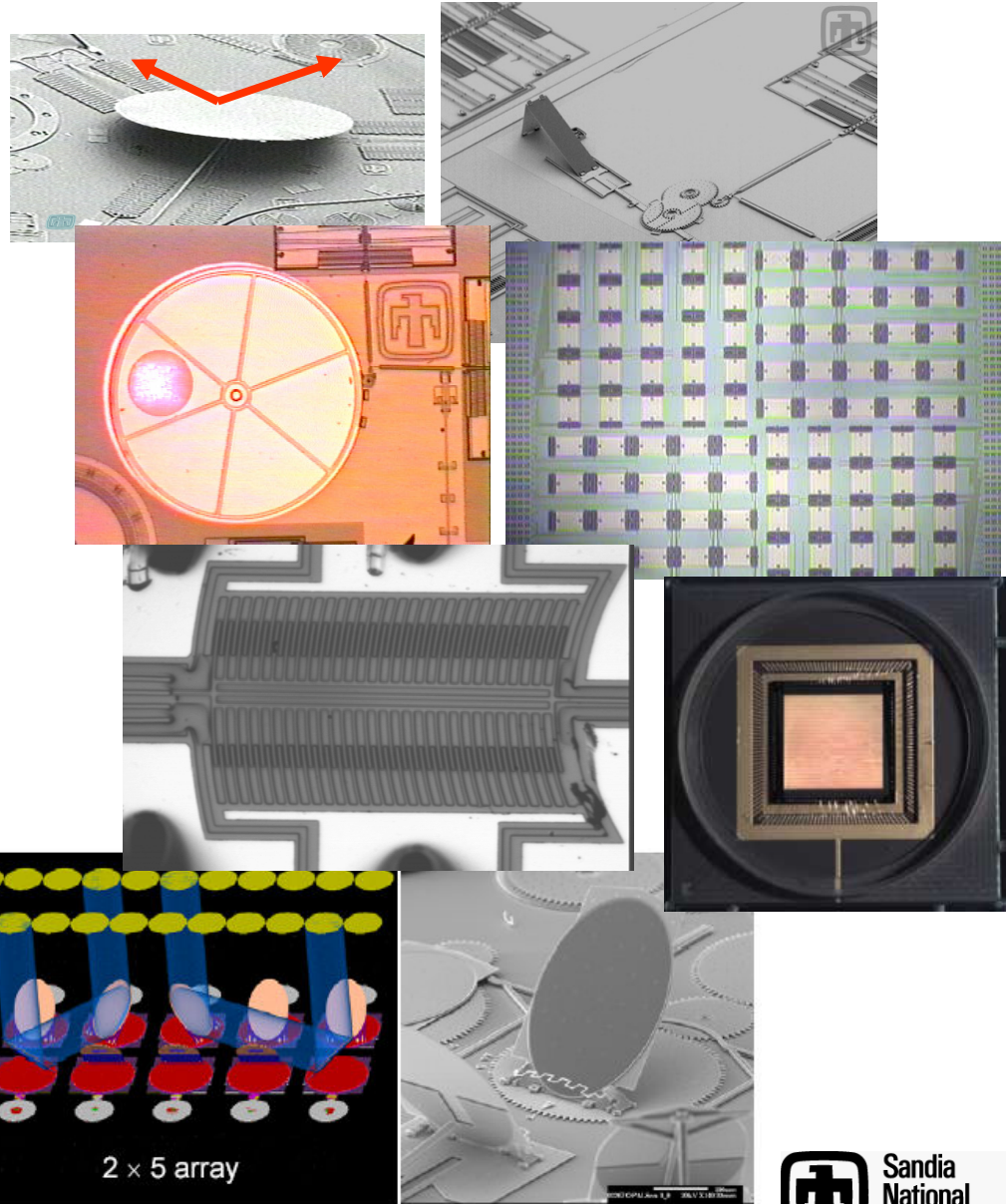
Primary Technology:

SUMMiT V with BEOL metallization
(Some III-V, SOI, etc.)

Projects Include:

- MEMS mirrors for optical beam forming (free space true time delay implementation)
- MEMS mirrors for hyper spectral imaging (Hadamard Transform Spectral Imager)
- MEMS mirrors for fiber optic cross connect for diagnostics and state-of-the-health monitoring (OPAL)
- MEMS mirrors for adaptive optics (Ultra-Light Weight Next Generation Telescope)

No real attempt yet to integrate electronics and optical MEMS...but study is ongoing



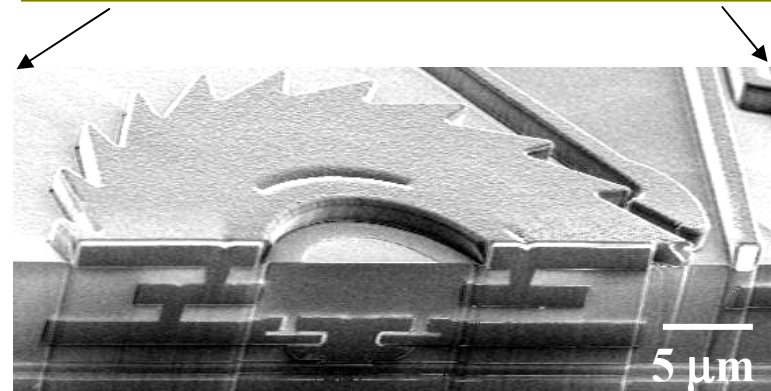
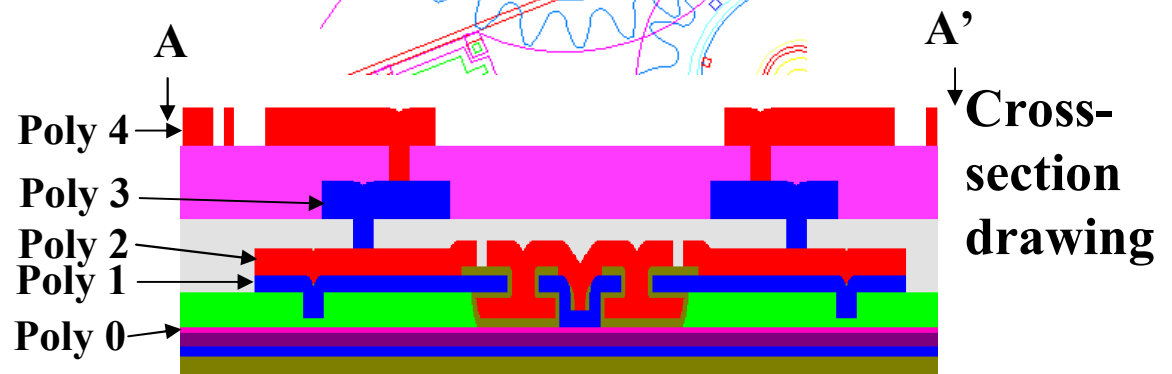
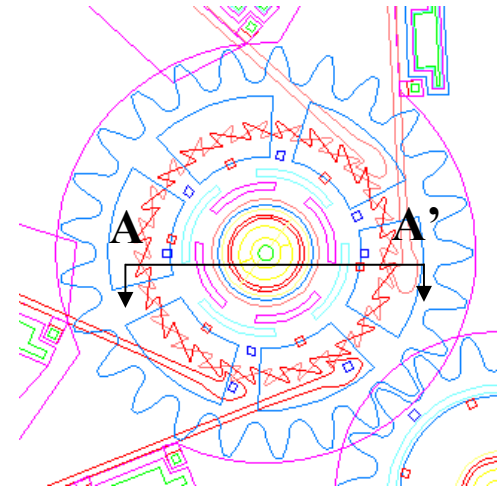


SUMMiT V™ Technology

Process features

- Polycrystalline silicon (Poly)
- Low stress (< 5 MPa)
- Conformal depositions
- high fracture strength (~ 3 GPa)
- Ground plane layer (Poly 0)
- 4 structural levels
 - (Poly 1 - Poly 4)
- Chemical Mechanical Planarization (CMP)
- $1\ \mu\text{m}$ design rule
- Technology accessible through SUMMiT foundry (SAMPLES)
- Custom BEOL specific to this program
 - metallization
 - packaging

Design

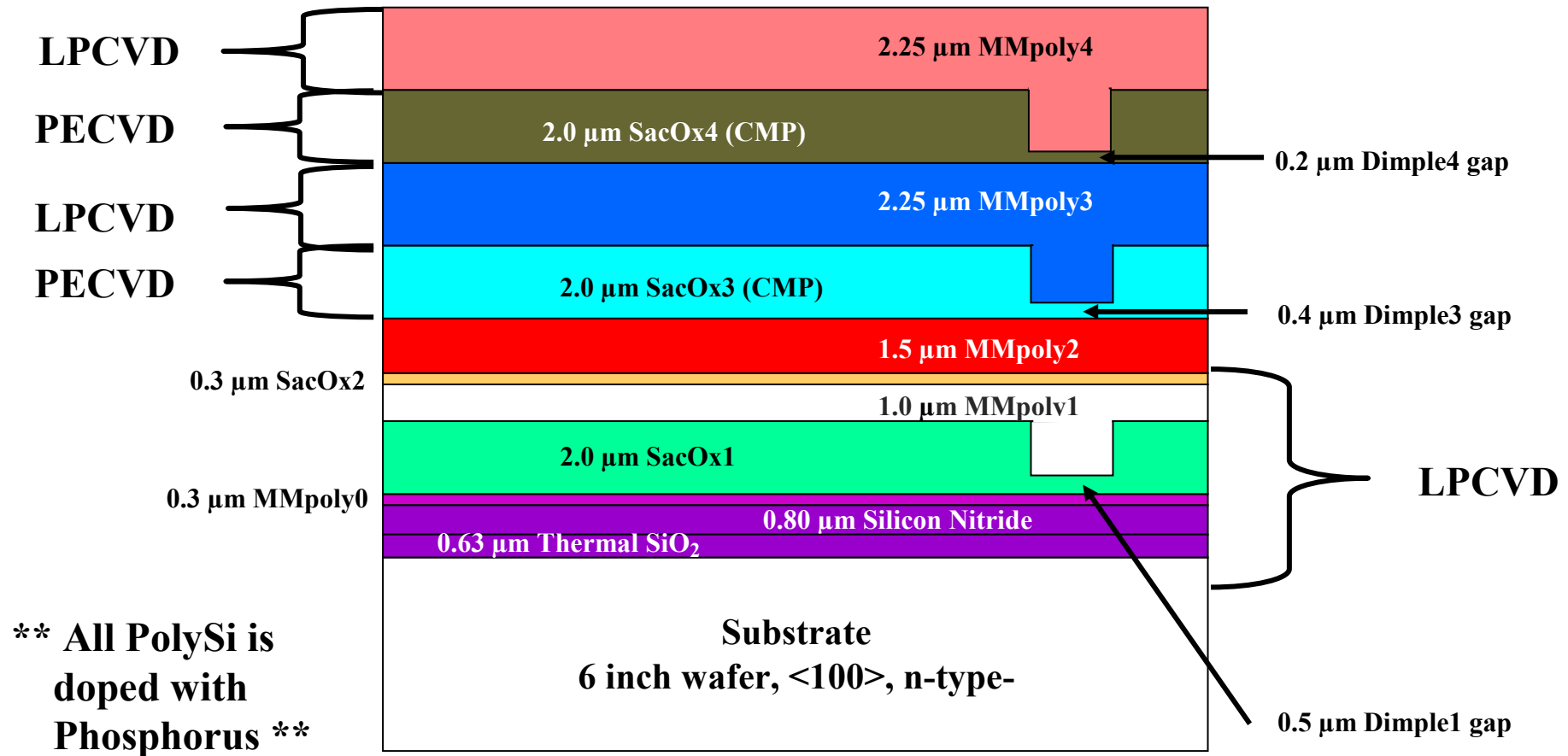


**FIB
cross-
section**





SUMMiT V™ - Sandia Ultra-planar Multi-level MEMS Technology

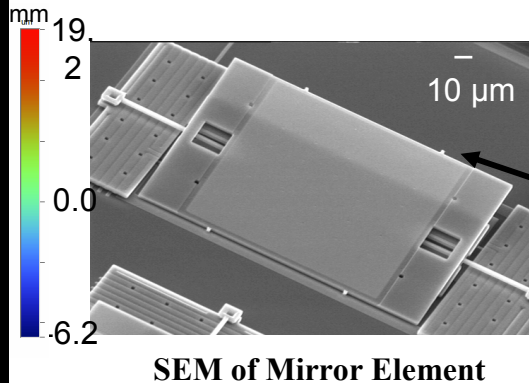
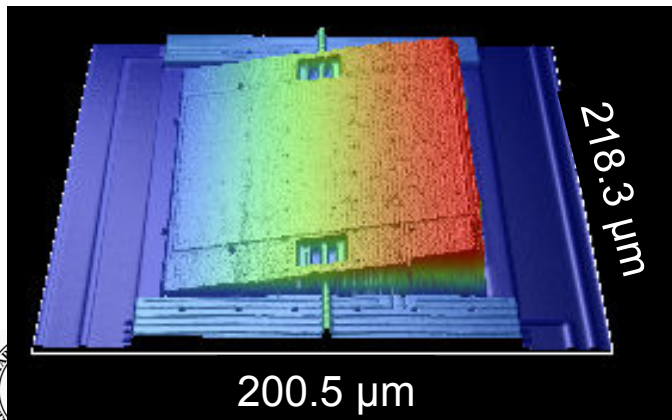
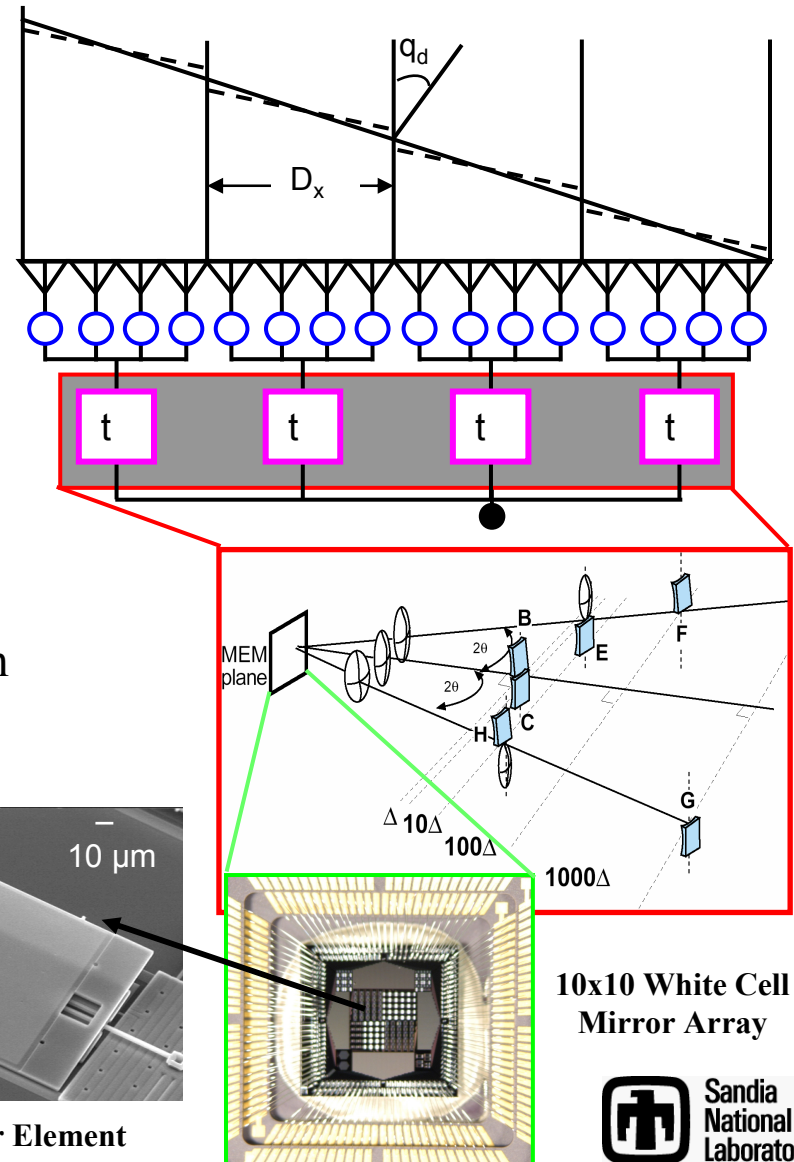




Sandia Beamformer Technologies

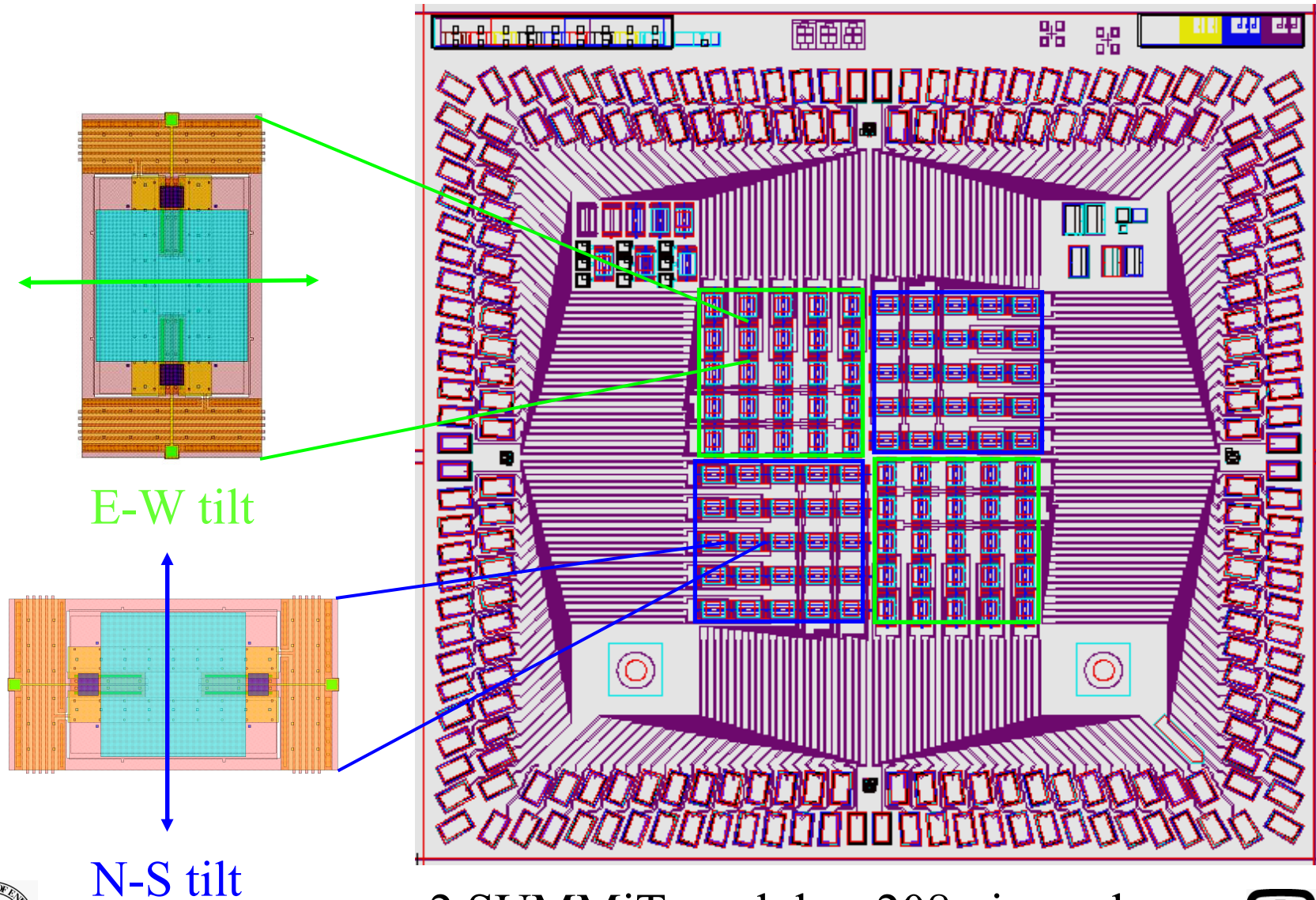
- Several possible approaches (fiber, magneto optical switch etc...) to implementation of optical time delay
- MEMS approach offers highest payoff
 - Most hardware compressive
 - <6dB for 10-bit (revised to 6-bit) dc-20GHz (ultra low loss)
 - Delays of 0.3-30nsec
- Demonstrated performance
 - 10 μ s switching for >100 μ m mirror
 - Tri-stable operation (-10° , 0° , $+10^\circ$)
 - 10^9 cycles without failure on packaged arrays
- System demonstration of selected time delays in 0.2 – 20 nsec range with 1.25 psec resolution (with OSU)

Hybrid Architecture Concept





10x10 Mirror MEMS Array

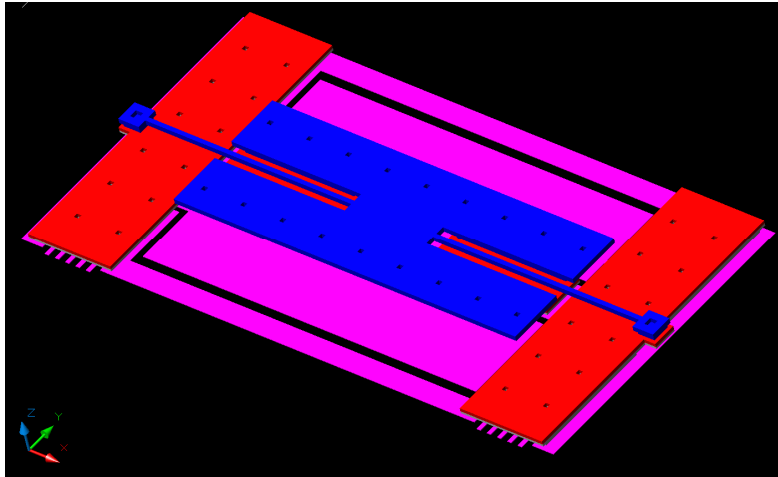


2 SUMMiT modules, 208 pin package

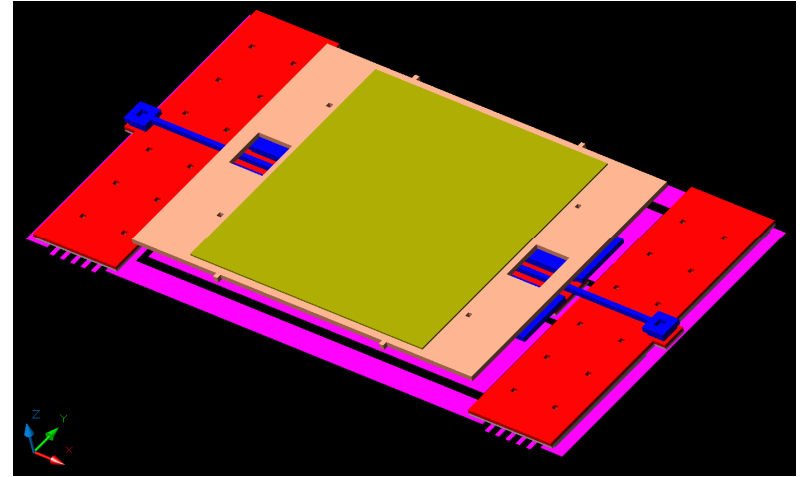




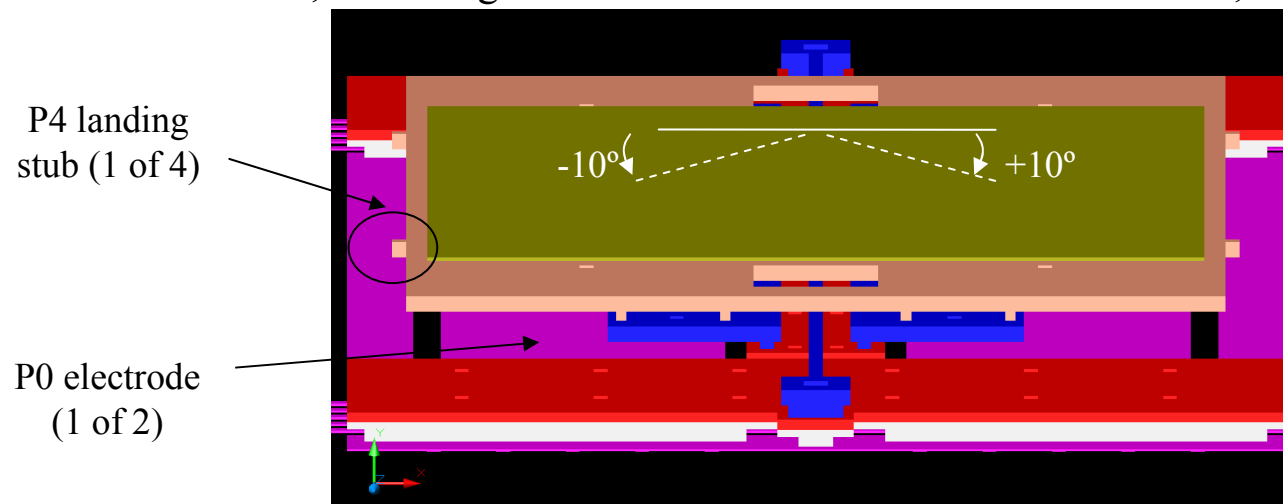
3-D view of the mirror



Mirror3, P0 through P3



Mirror3, P0 through Metal

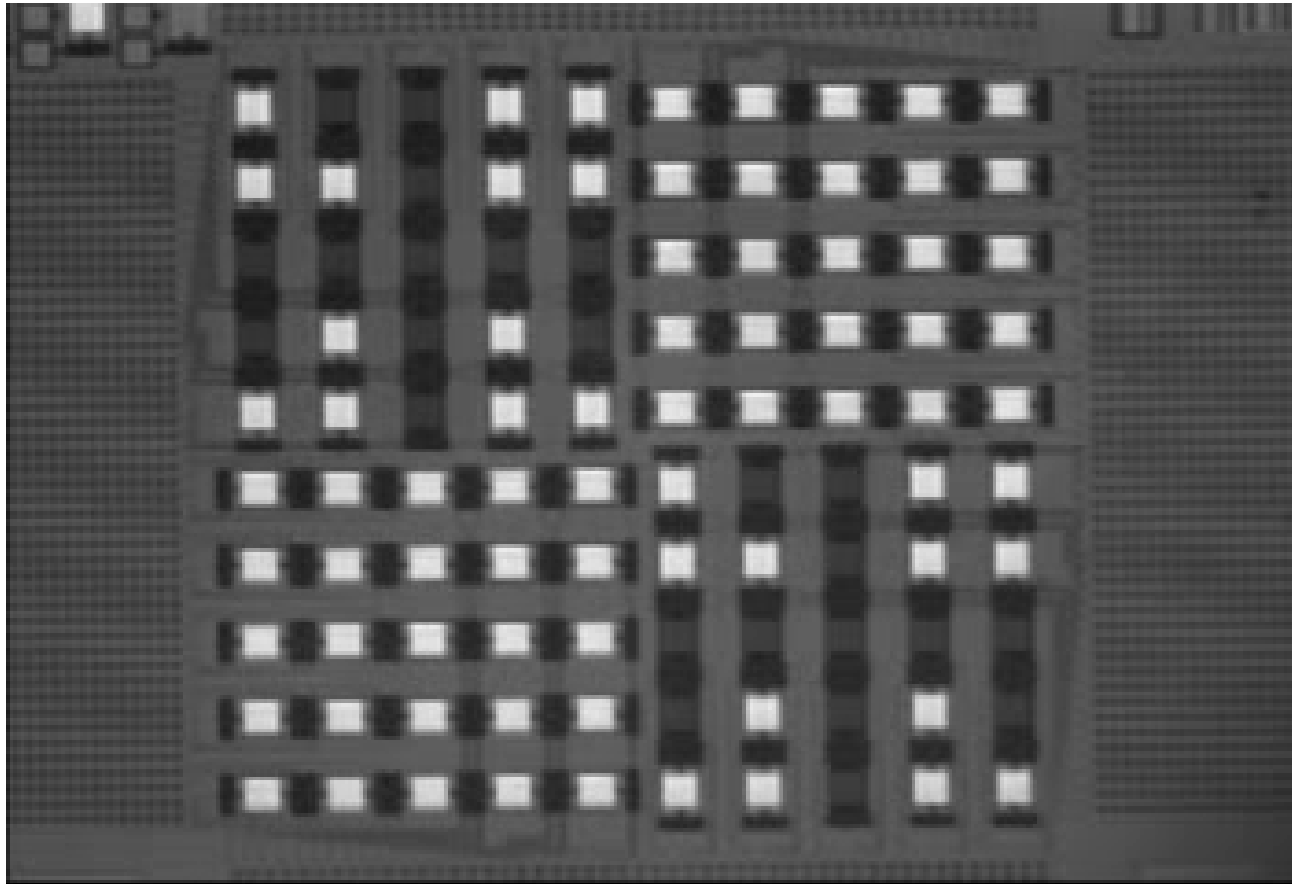


Mirror3 end view, P0 through Metal



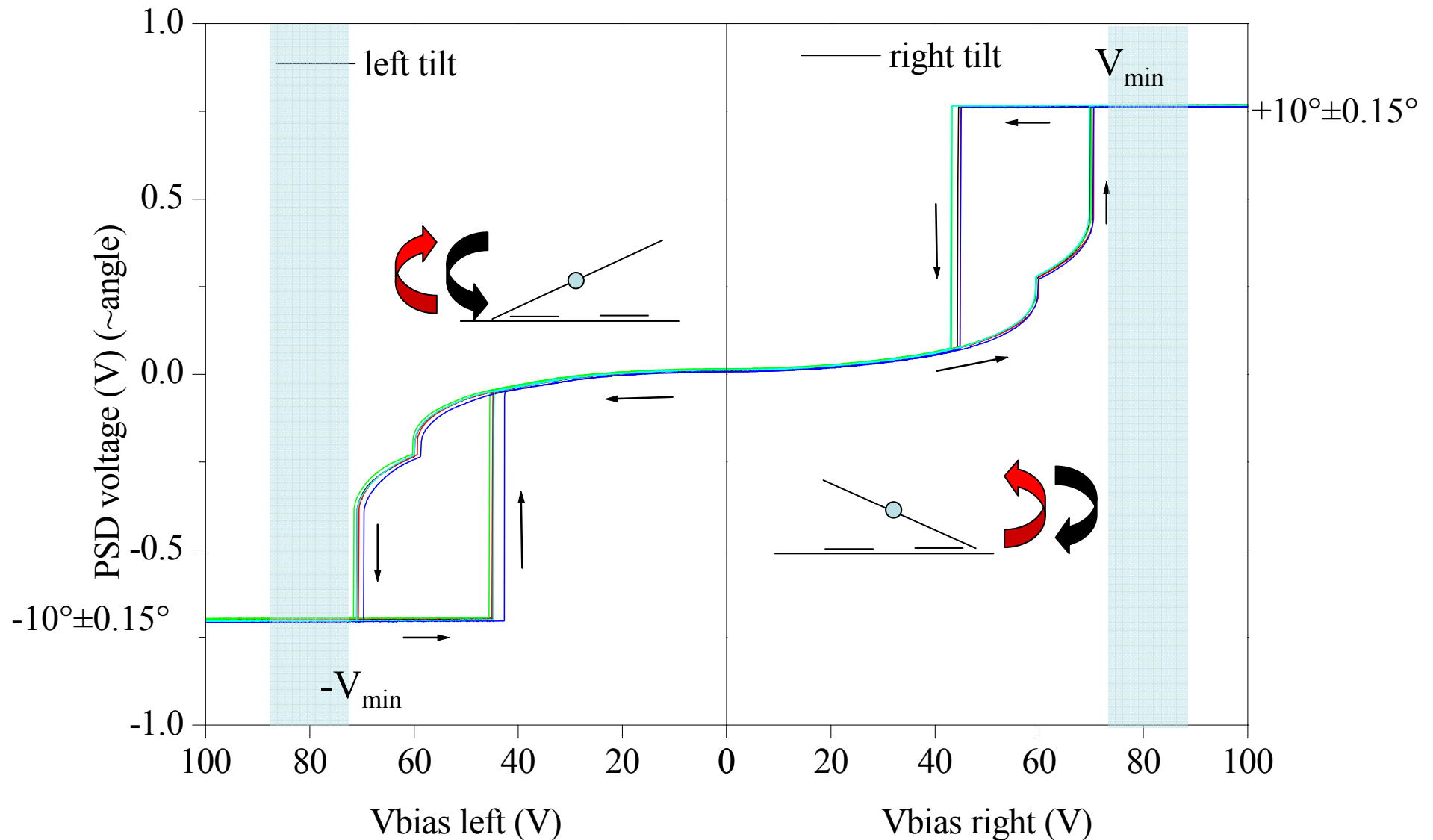


MEMS Array Image





Static Voltage Response of Five Mirrors



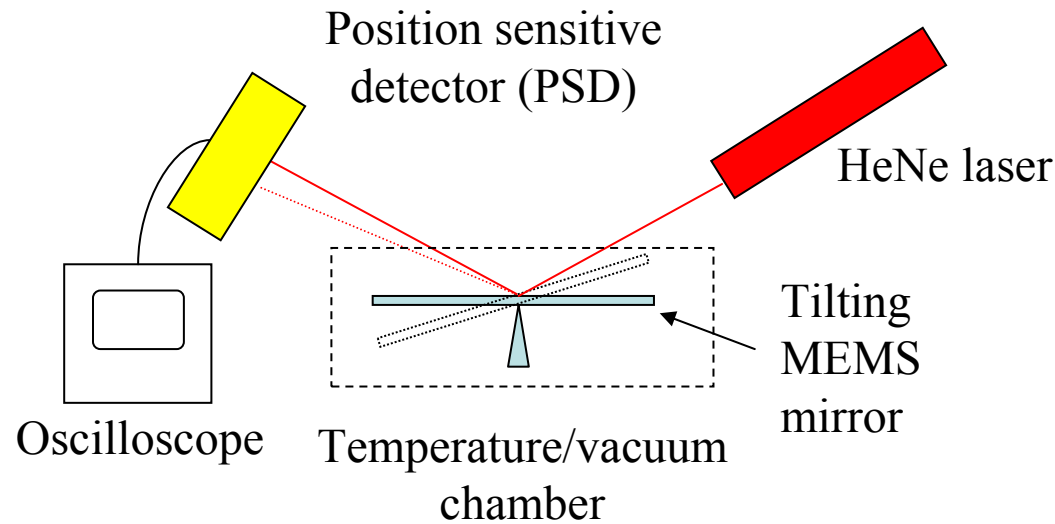
- Good uniformity between mirrors
- Hard stops at $\pm 10^\circ$ ensure insensitivity to bias voltage





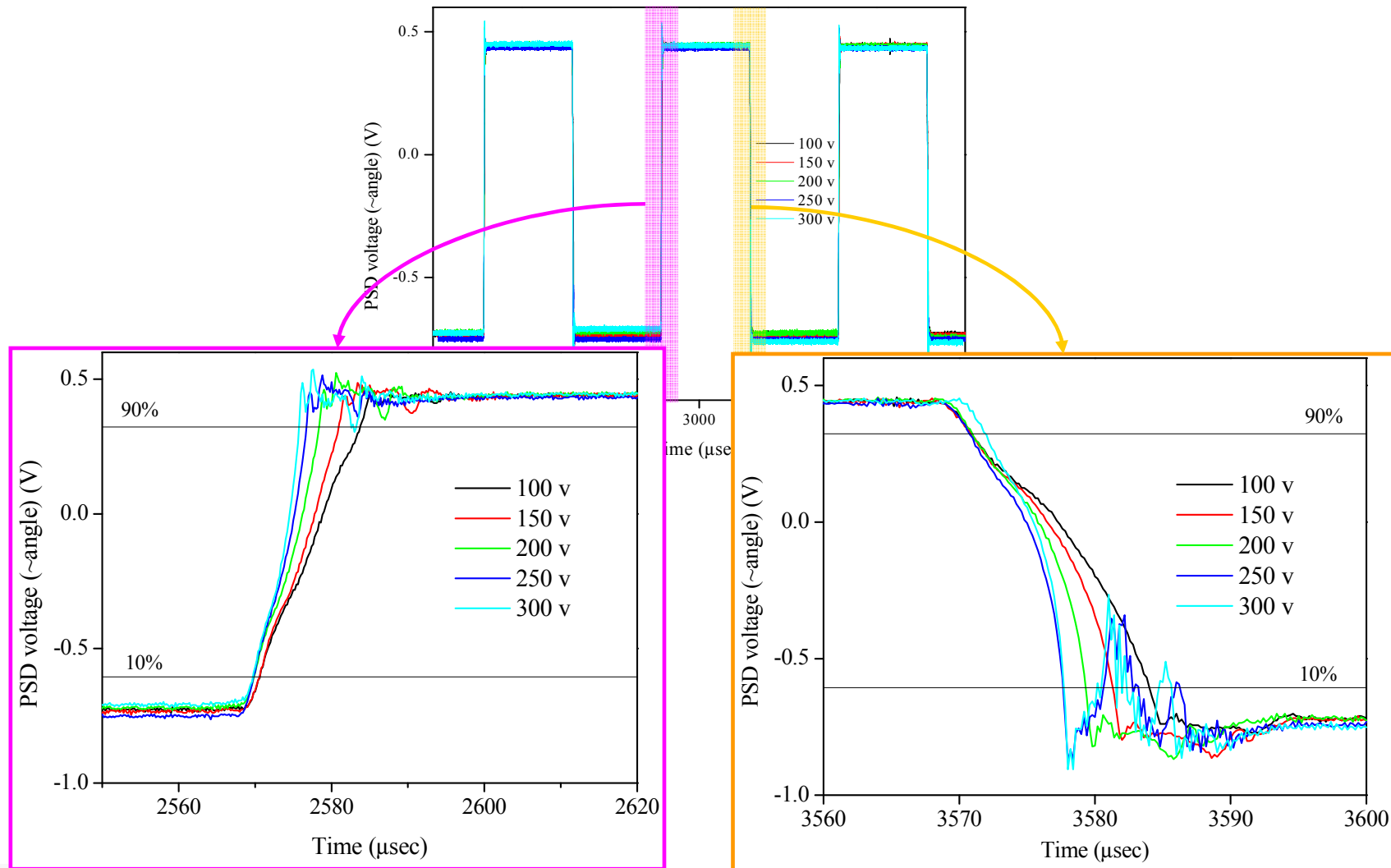
Switching speed

- Switched bearing to bearing (-10° to $+10^\circ$)
- Switching speed determined by time to traverse 10% to 90% of total angular swing
- Simple square waves applied to left and right pads 180° out of phase - nothing fancy
- Fastest response times most likely limited by unoptimized drive and detection electronics – new electronics underway





Bearing to bearing switching speed (-10° to $+10^\circ$)

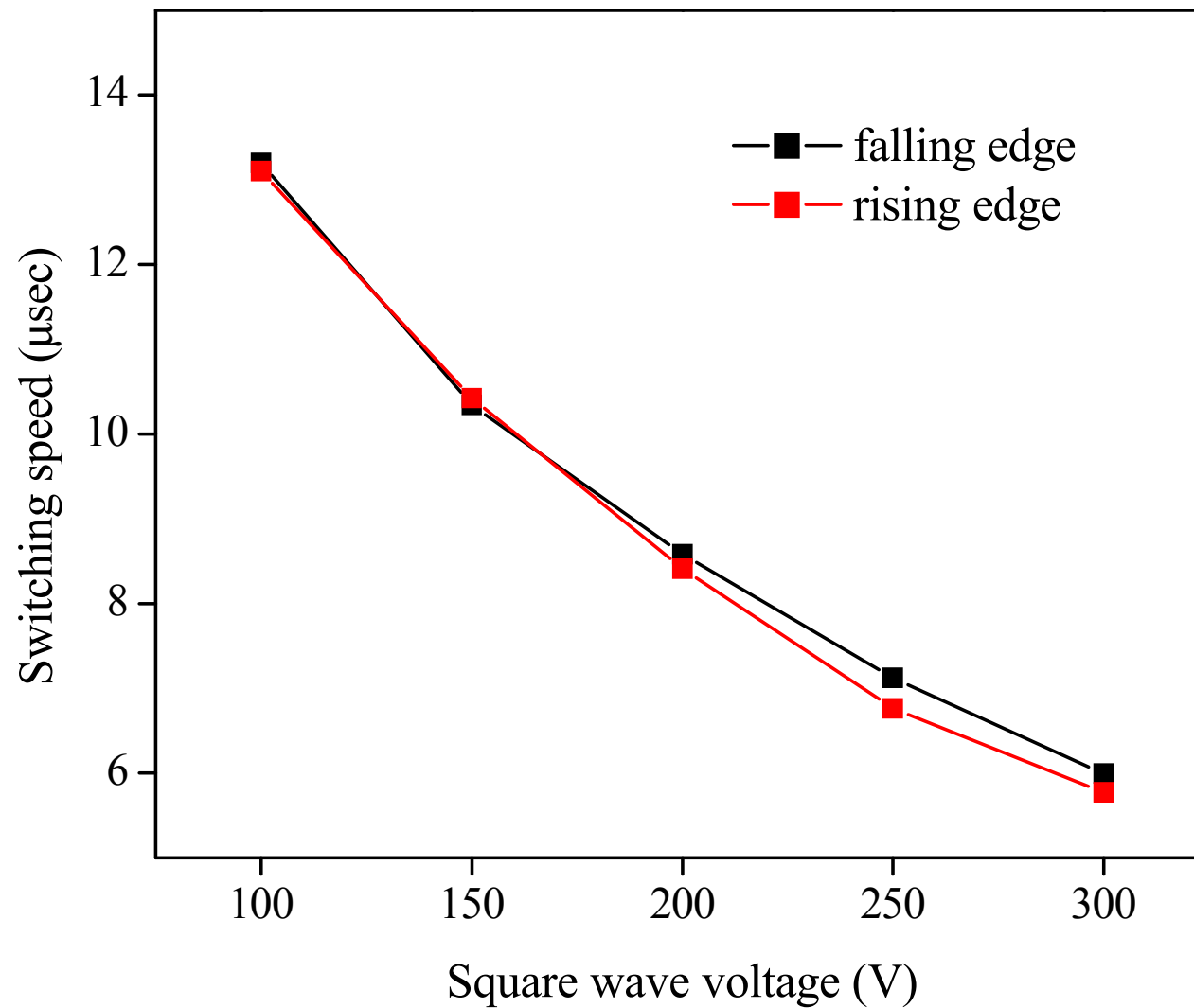


Driven by square waves of increasing amplitude



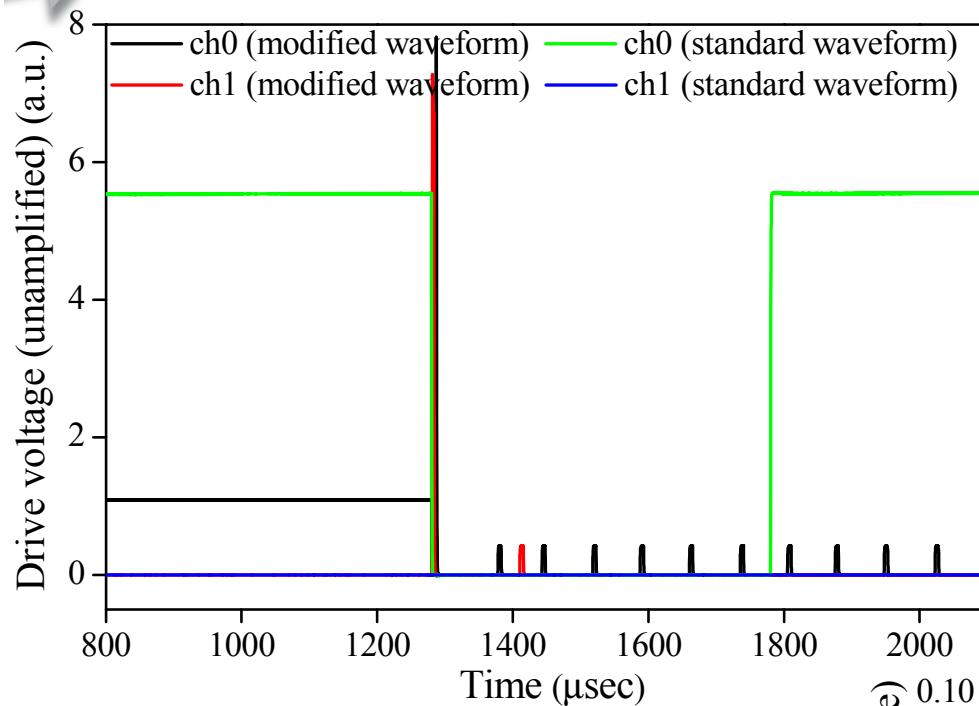


Switching speed vs. applied bias





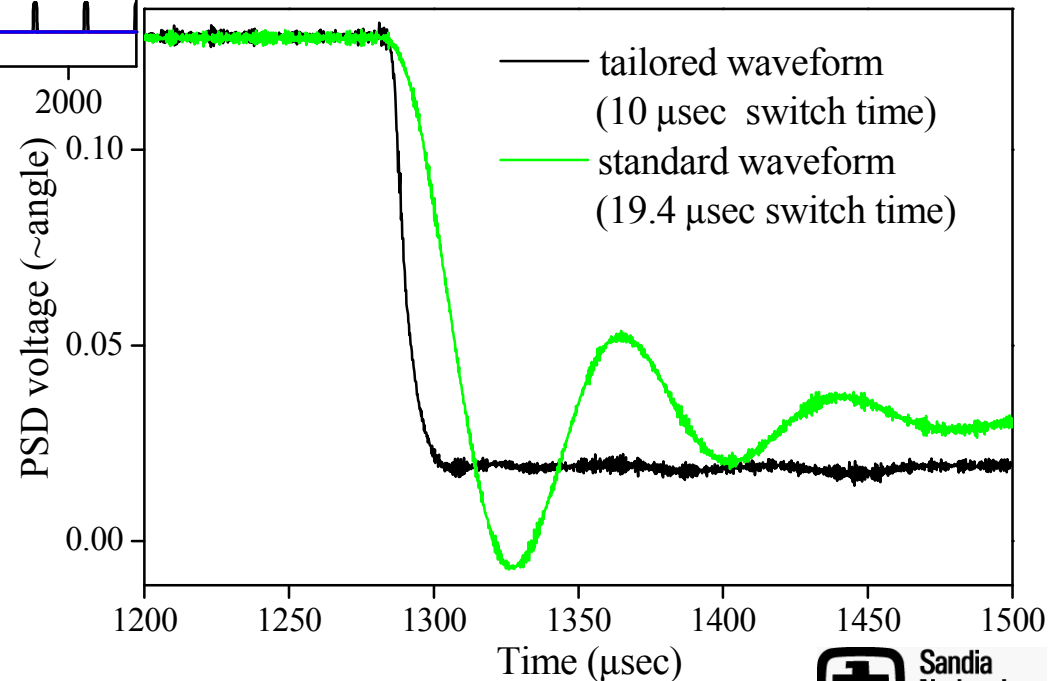
Modified vs. standard waveforms



- Different switch structure: switch angles -2.5° to $+2.5^\circ$
- Also possible bearing to bearing switching with soft landing – hit the substrate at 0 velocity without sacrifice in switching speed

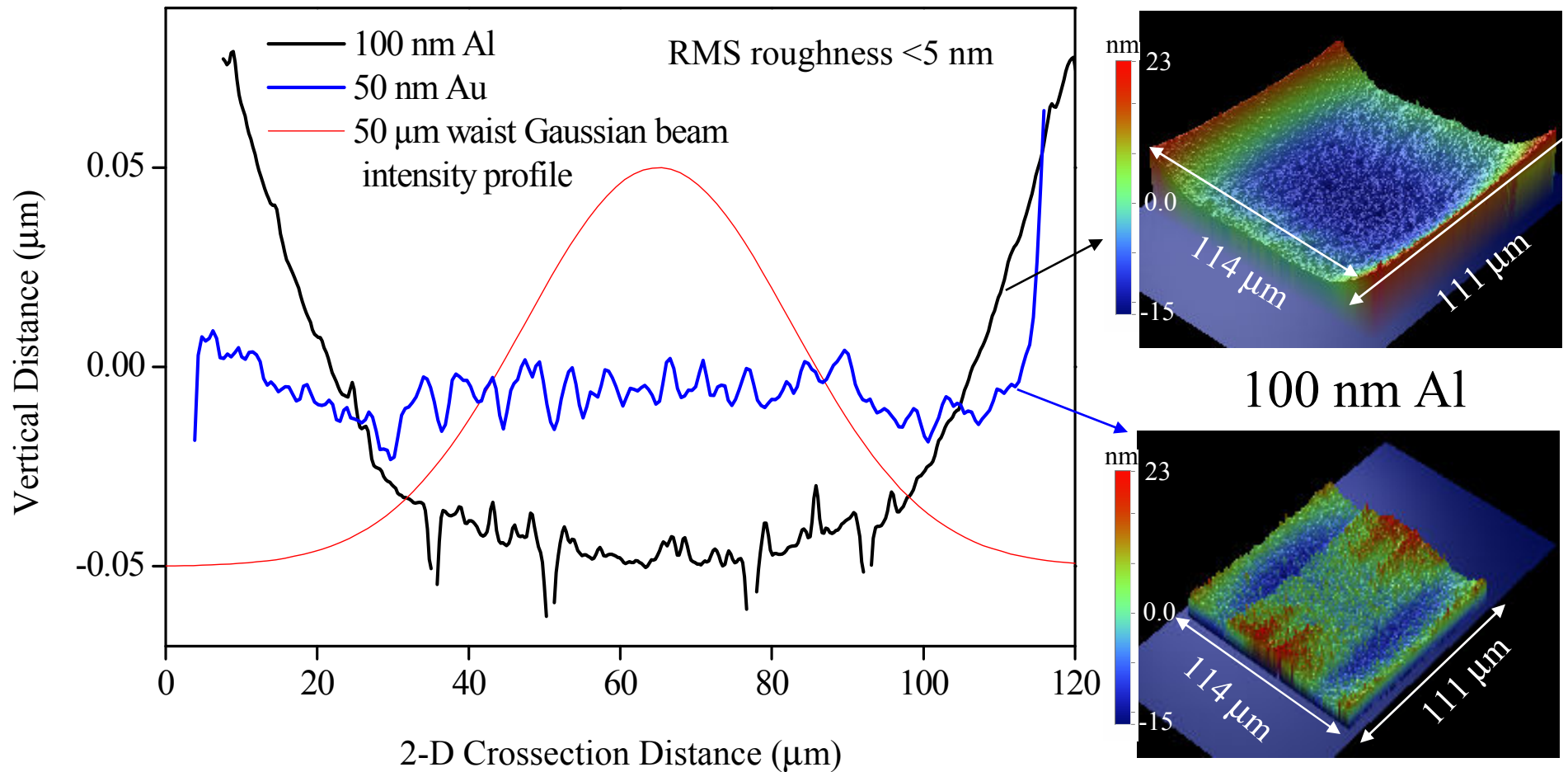
Refinements in switching speed

- Switch 10° to 0° - problem with ringing at 0°
- Electrostatic damping to remove ringing (modified vs. standard waveforms)





Surface Quality of Mirrors

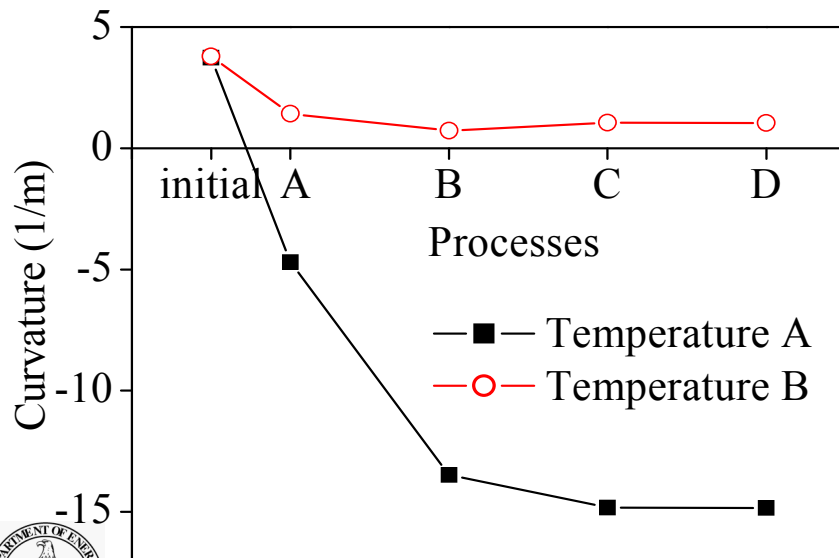
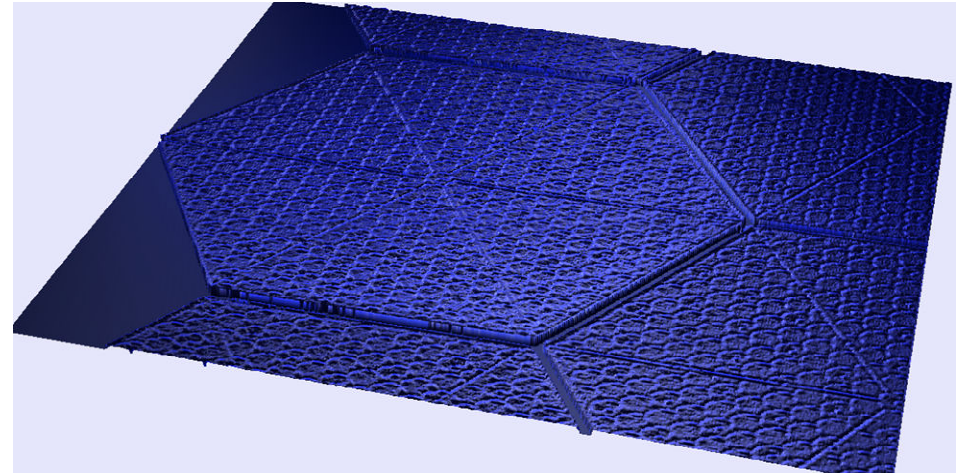
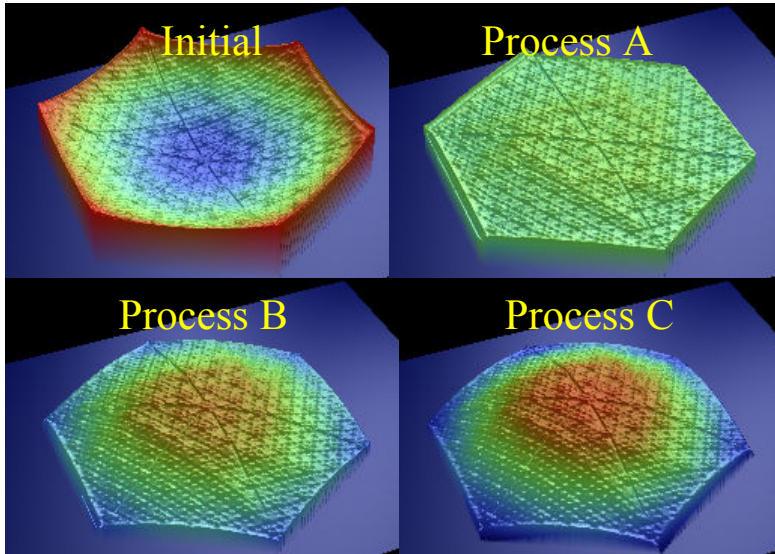


- Characterized mirror surfaces to predict the impact on system performance

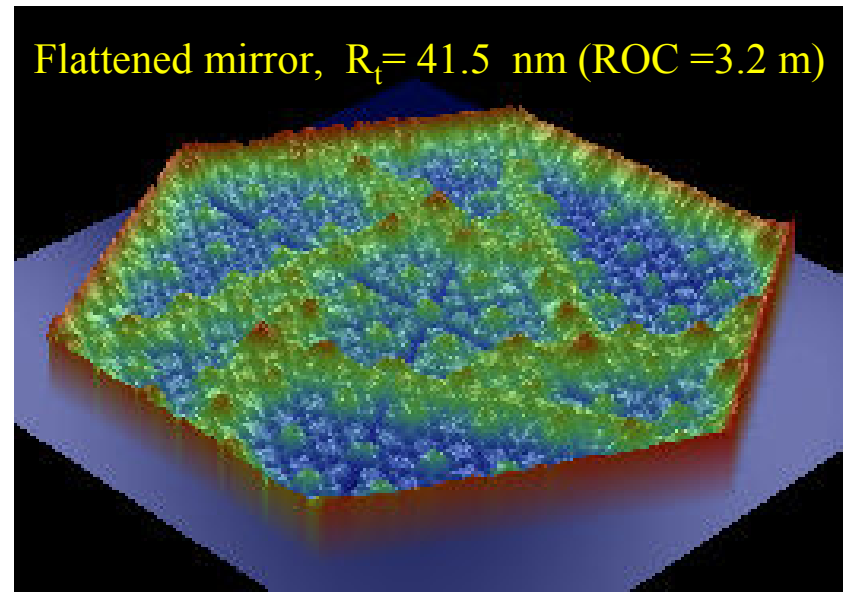




Mirror Surface Quality

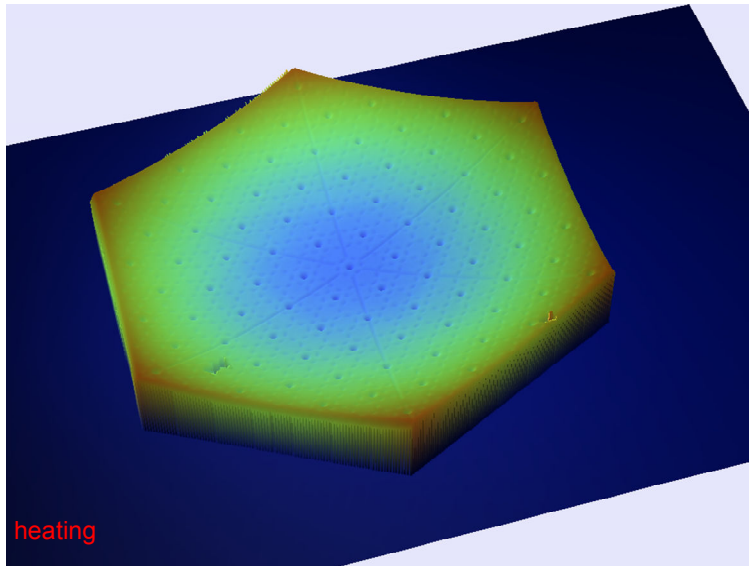


Flattened mirror, $R_t = 41.5 \text{ nm}$ (ROC = 3.2 m)

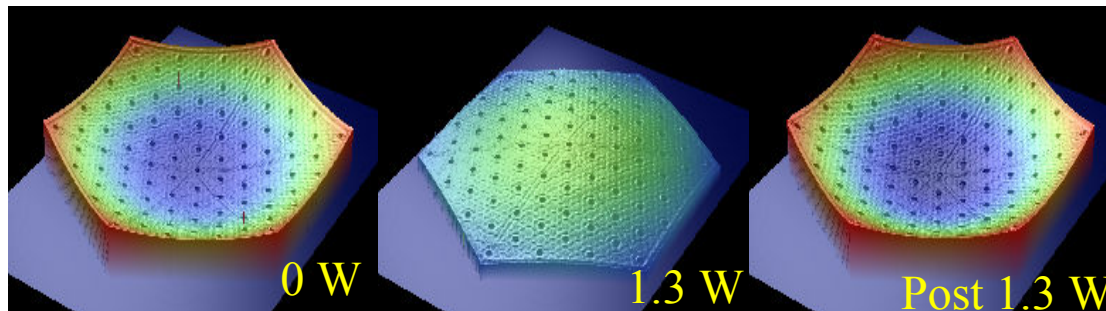
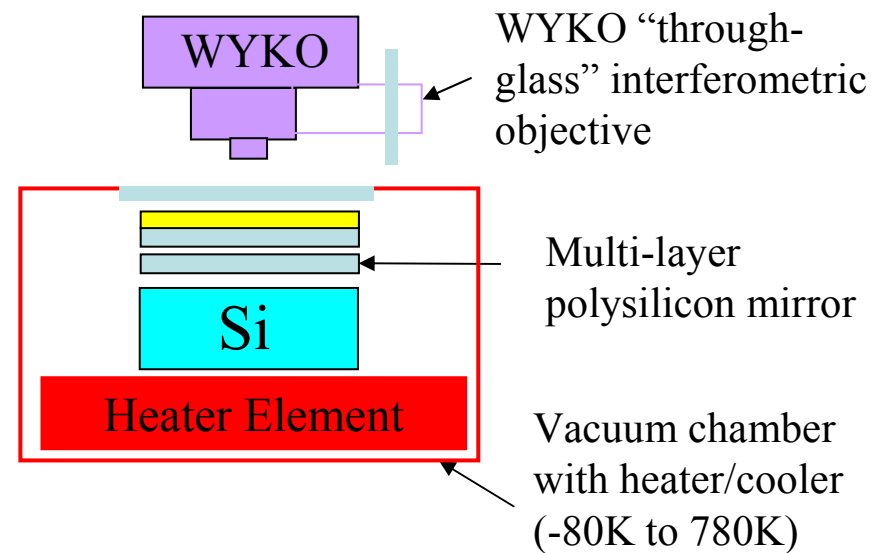




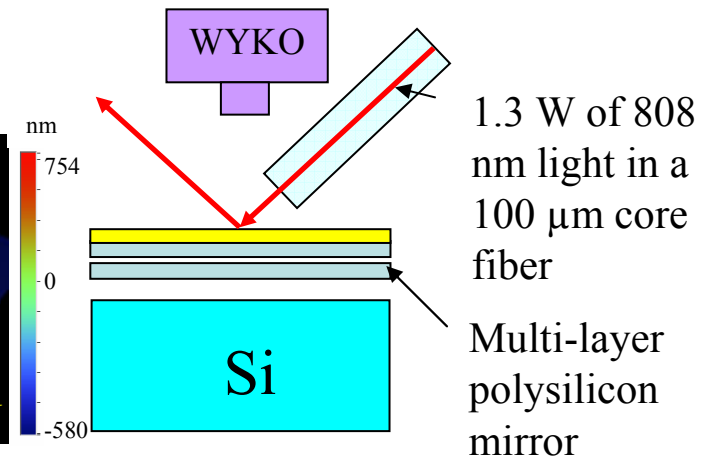
Temperature and high optical power effects



Ambient heating

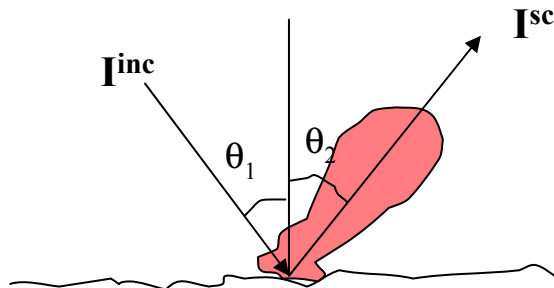
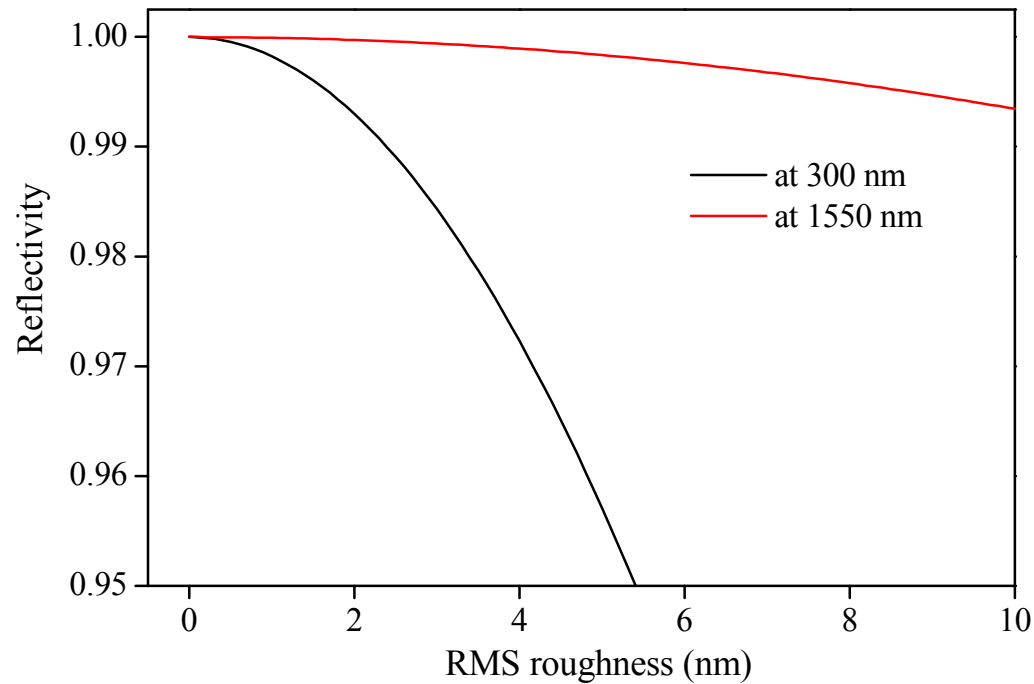


Laser heating (1.3 W \rightarrow 2.8 kW/cm²)

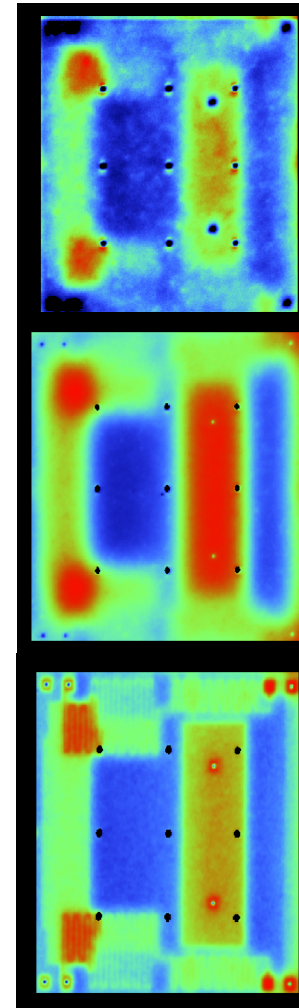




Influence of mirror roughness



$$\langle I_{sc} \rangle = I_0 e^{- (4\pi\sigma \cos\theta_1 / \lambda)^2} + \langle I_d \rangle$$



Rq=2.43 nm

Rq=14.95 nm

Rq=19.6 nm

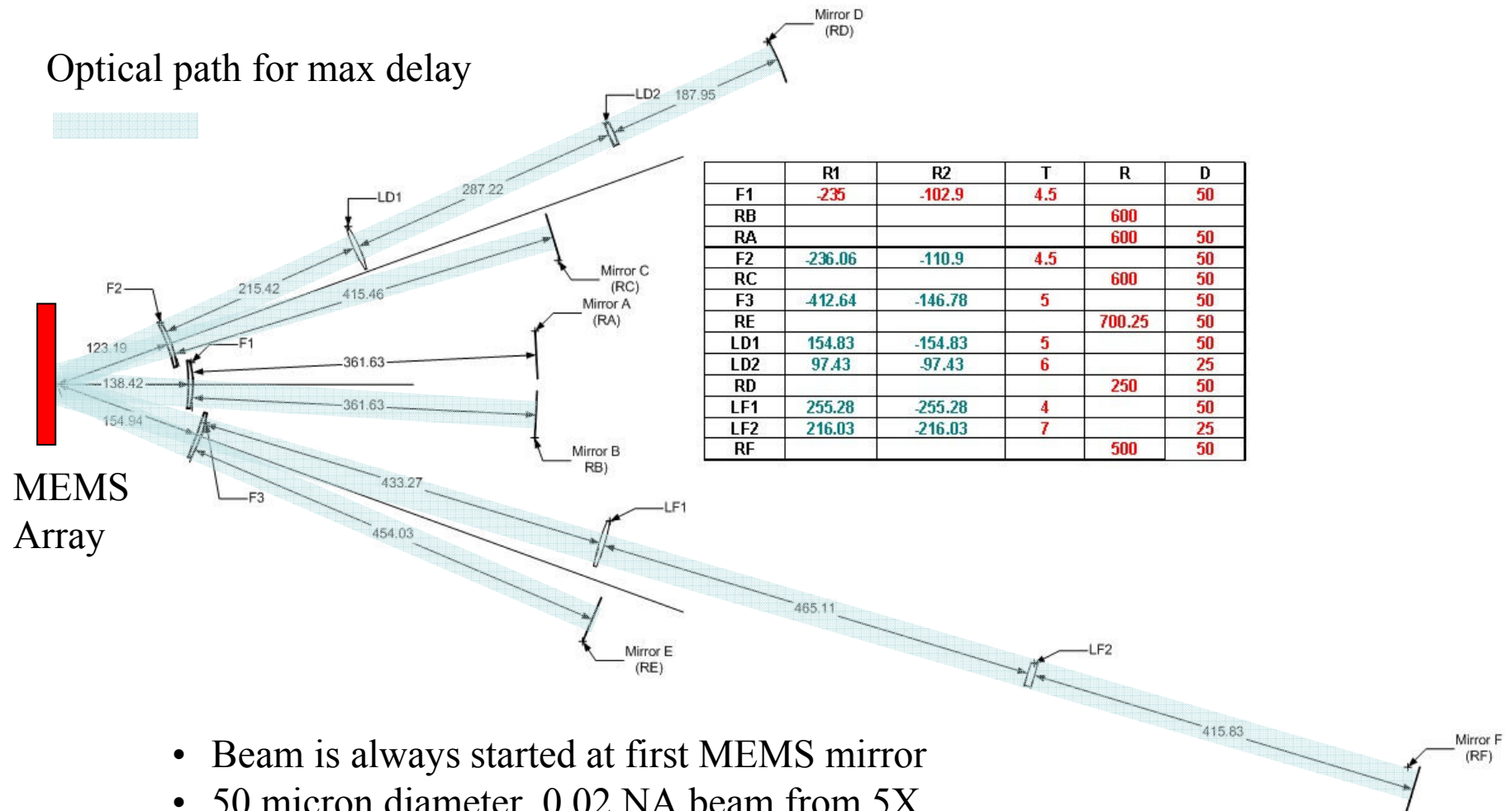
Effect of process modification





Starting point for quartic cell model

Optical path for max delay



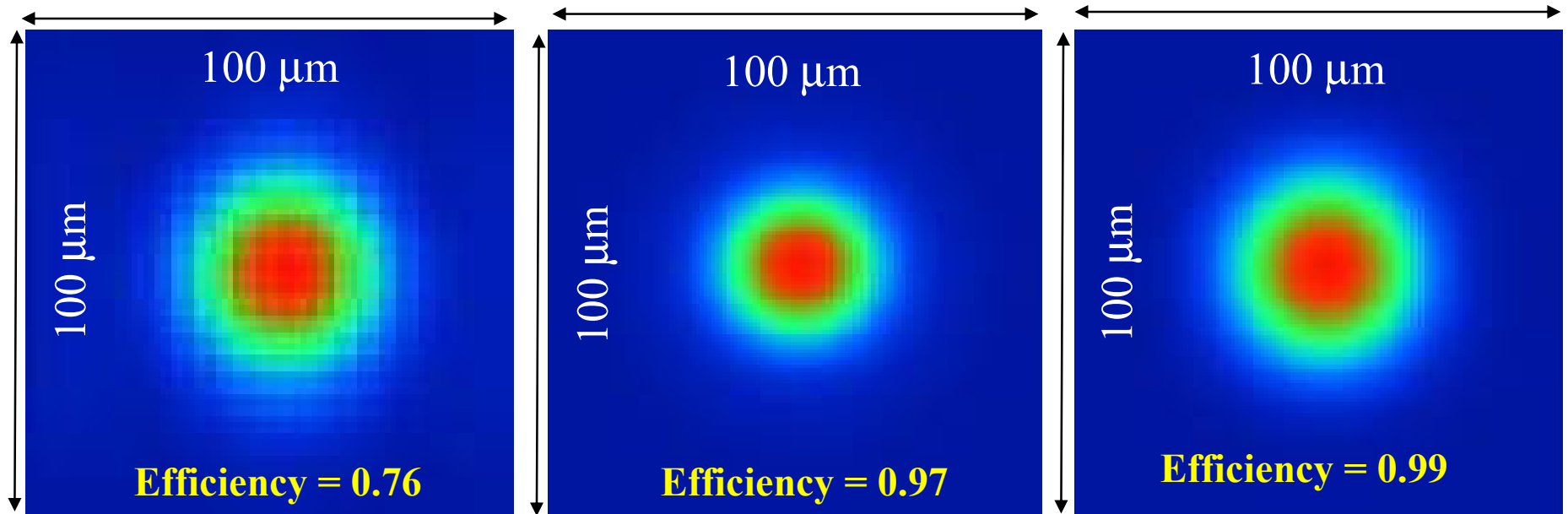
- Beam is always started at first MEMS mirror
- 50 micron diameter, 0.02 NA beam from 5X magnification of 10 micron, 0.10 NA fiber
- Wavelength is 1.55 microns





ZEMAX™ Model of White Cell

Modeled spot on the last MEMS mirror after acquiring maximum optical delay 10 bounces on MEMS mirrors



Optics aberrations only
(Ideal MEMS mirrors)

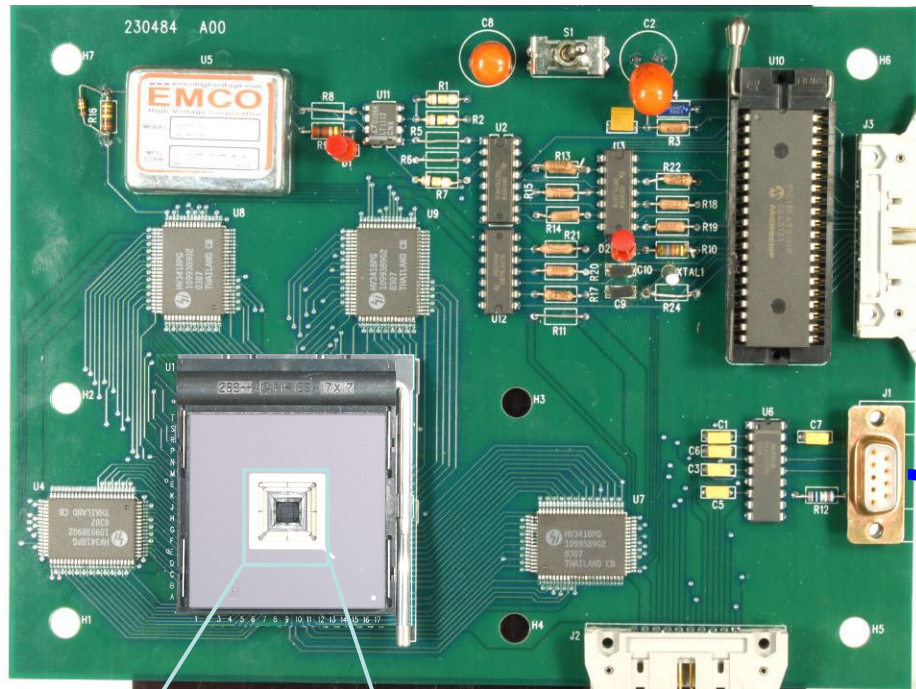
Al metallized MEMS
aberrations only

Au metallized MEMS
aberrations only

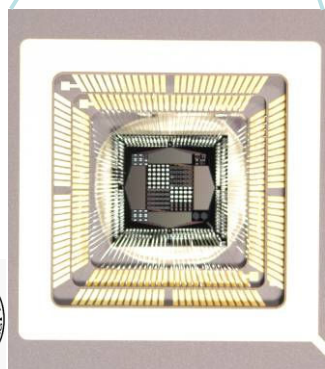




MEMS Package, Drive Electronics and Control Software

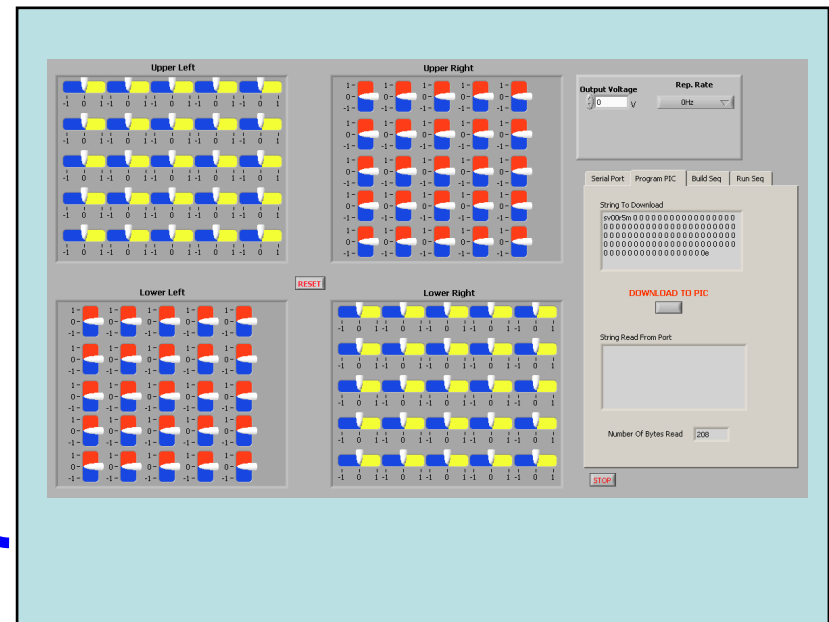


Research prototype drive electronics board



MEMS chip
packaged in a
208 pin PGA

RS232



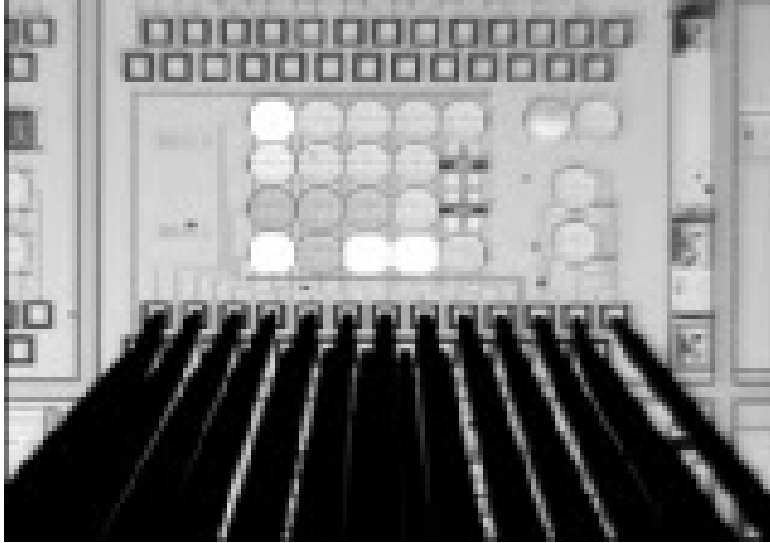
Control software

A complete optical
subsystem for laboratory
demonstration

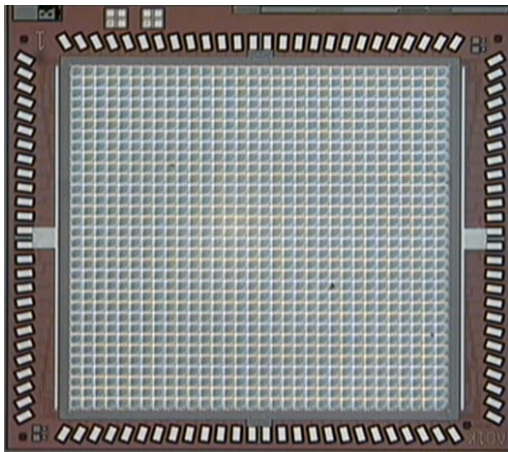




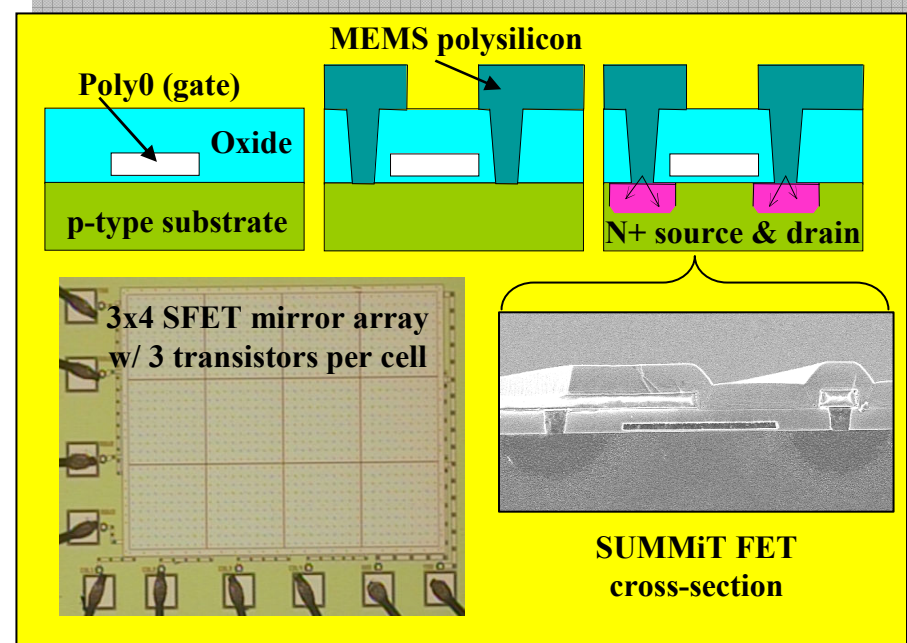
MEMS/SFET Integration



SFET driven mirror array (movie)



SFET driven 32x32 piston mirror array for AO

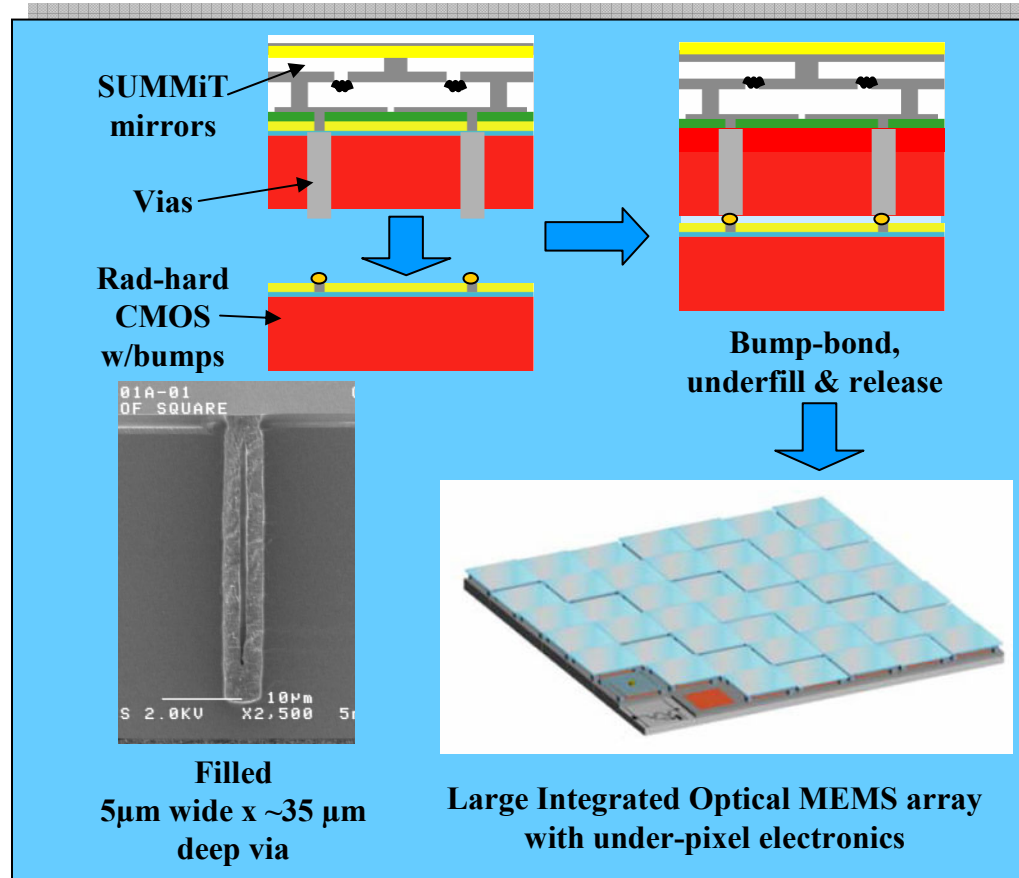


- SFET (SUMMiT FET)
 - WFO supported as risk mitigation task
 - Goal: SUMMiT OMEMS w/ integrated NMOS electronics
 - Demonstrated actuation of 12 and 20 mirror arrays, scale up to 1600 element array (40x40) for brass board demo

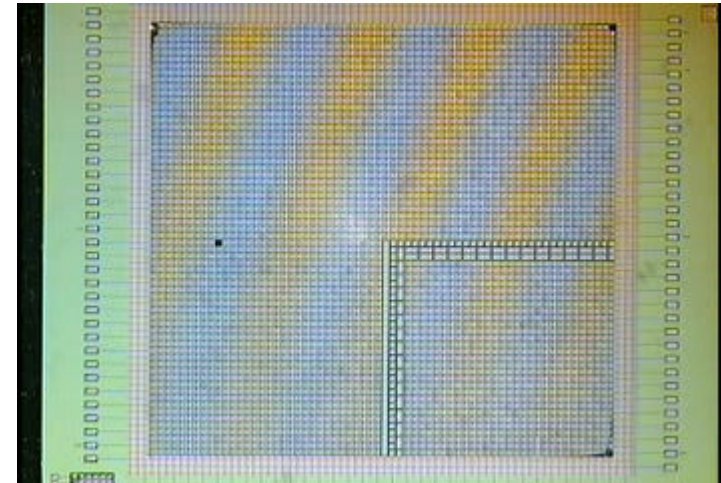




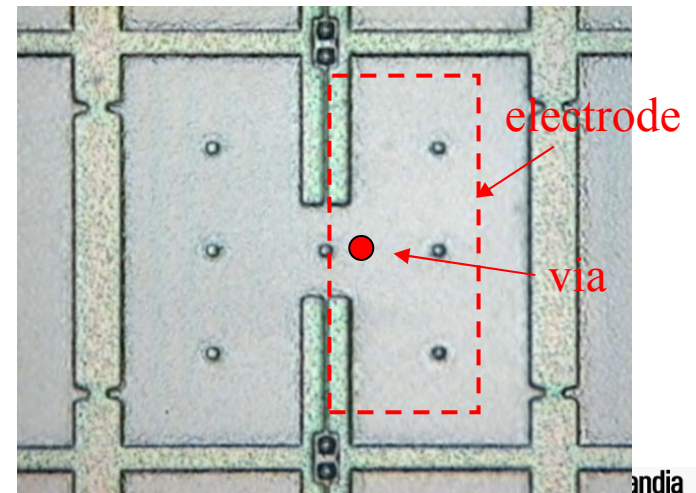
Heterogeneous integration: vias



- Goal: 4096 SUMMiT mirrors w/vias bump bonded to underlying electronics
- Demonstrated actuation of 4096 mirrors with linked vias



Movie of tilting mirror array interconnected by 4096 vias

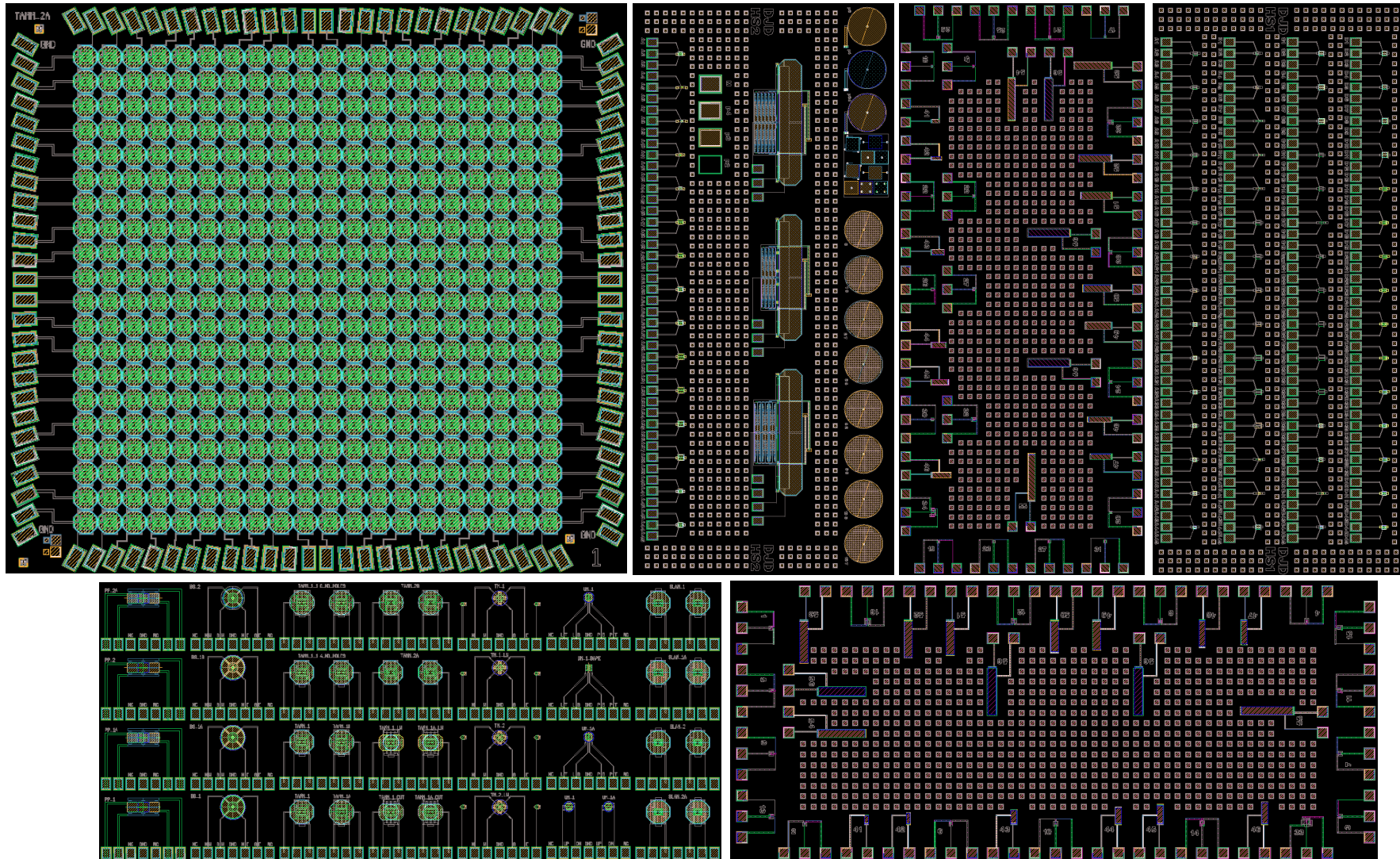


Individual tilting mirror





Faster MEMS mirrors designs

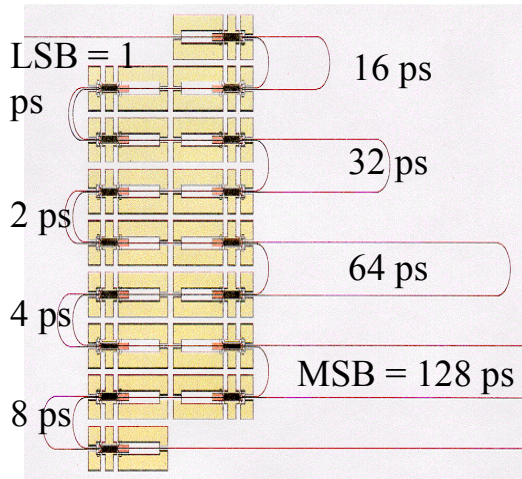


Mirrors varying from 20-250 mm, angles 1.5° - 2.8° ,
designed for speeds 0.1 – 100 μ sec

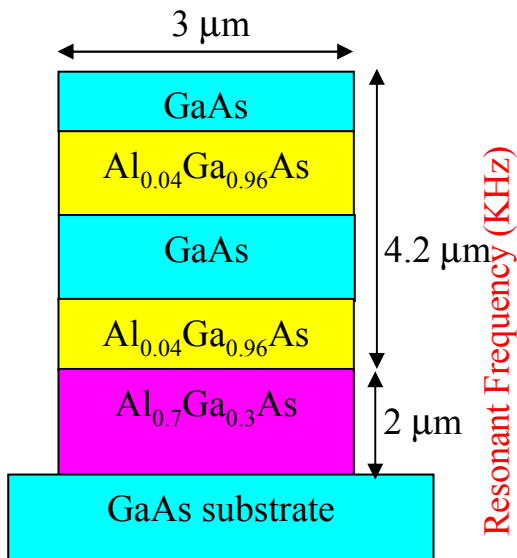
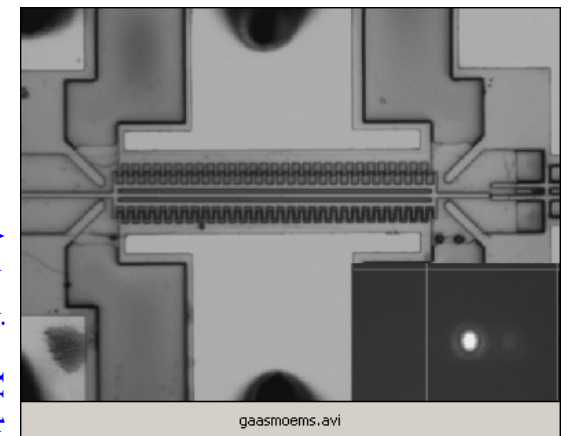
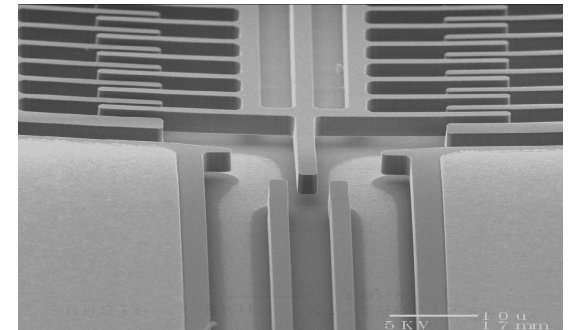
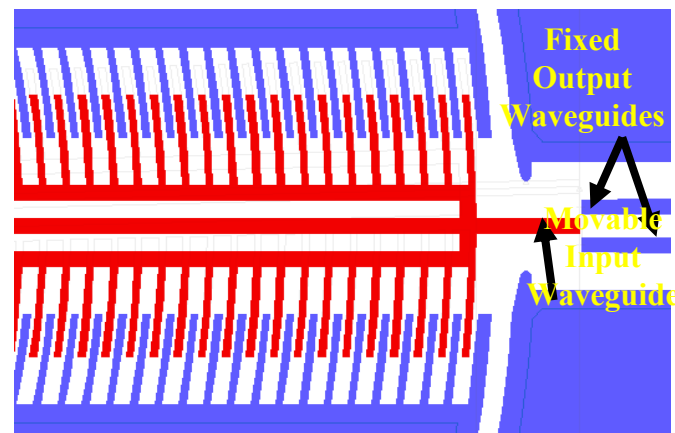




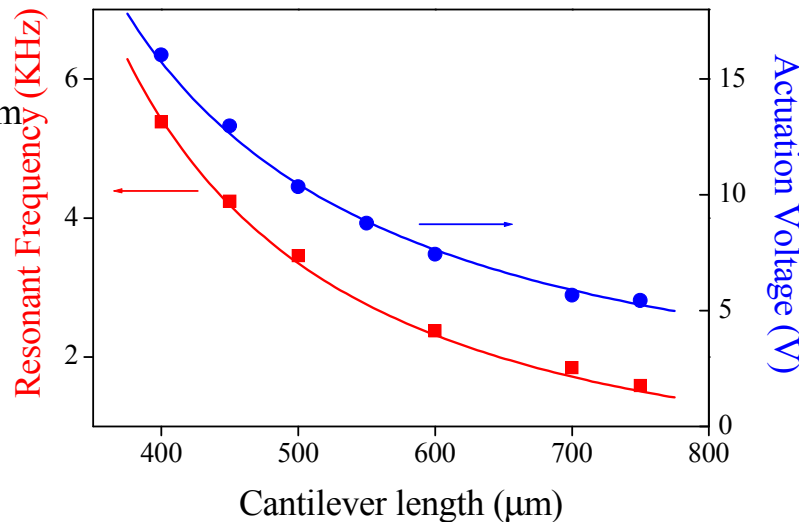
Compound semiconductor waveguide MEMS



Applications: optical time delay, optical sensors, on-chip signal routing and multiplexing (especially if monolithically integrated with lasers and detectors)



Cantilever cross section



Waveguide Switch

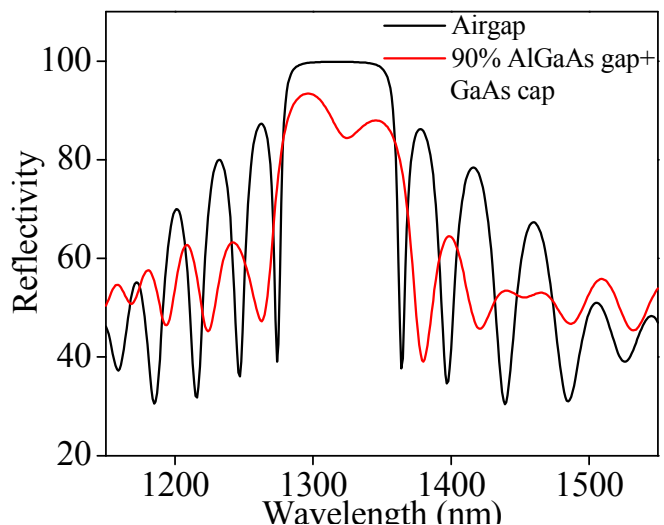
- $T_{\text{switch}} \sim 50 \mu\text{sec}$ (350 μm guide)
- switch loss = 0.8 dB (w/o insertion loss)
- 4 V < bias < 12 V



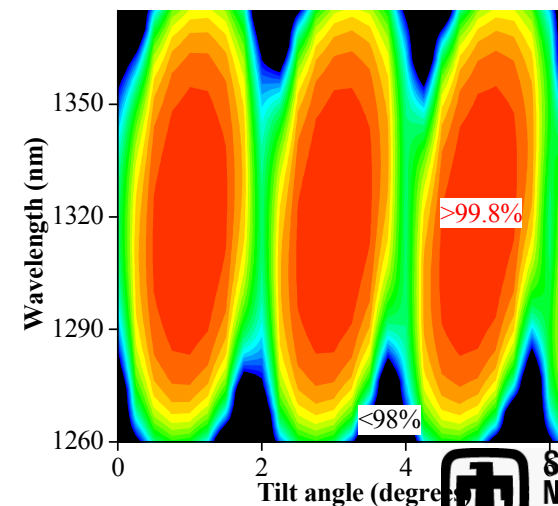
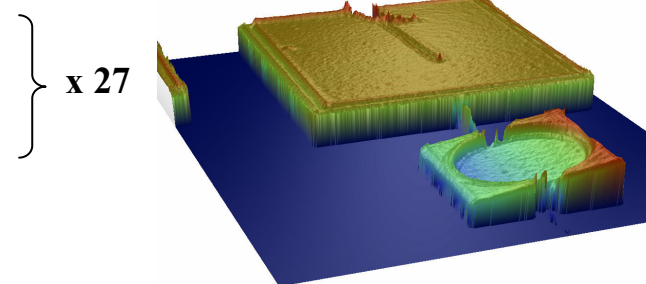
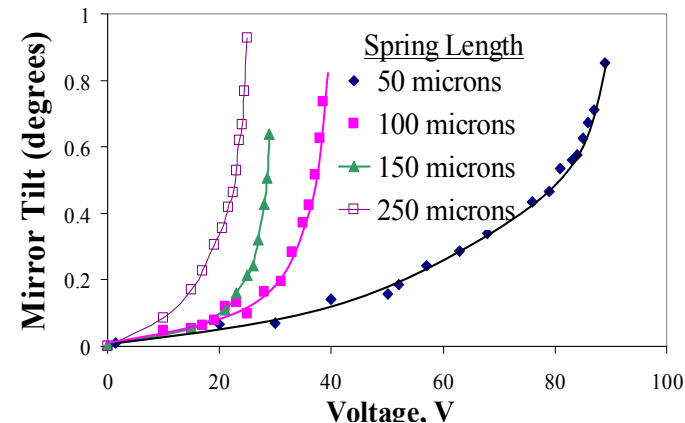
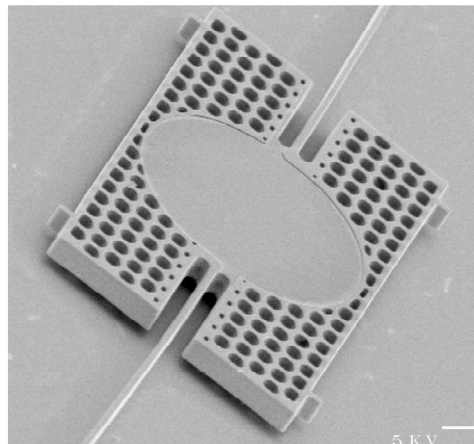
Compound semiconductor surface normal MEMS

High Reflectivity Tilt Mirror (HiRTM)

- Designed for $R > 98\%$ for all angles
- Tilt angle $\sim \pm 3.4^\circ$
- Predicted tilt bias $15 > V > 5$ for 300 μm long springs



GaAs 1000 Å, $n = 2 \times 10^{19}$
$\text{Al}_{0.45}\text{Ga}_{0.55}\text{As}$ 2078 Å
GaAs 968 Å
$\text{Al}_{0.5}\text{Ga}_{0.5}\text{As}$ 1047 Å
GaAs 968 Å
$\text{Al}_{0.9}\text{Ga}_{0.1}\text{As}$ 23080 Å
GaAs substrate n^+





Conclusion

- Sandia is involved in a variety of optical MEMS programs
- Existing surface micro-machined MEMS mirrors switch in 10 μsec
 - New designs for faster switching speeds ($<0.1 \mu\text{sec}$) currently in fab
 - Advanced control algorithms for enhanced switching speeds and dynamic control have been implemented
- High reflectivity MEMS mirrors possible, but challenging for UV wavelengths
 - Mirror figure can be controlled by post-processing techniques
 - Mirror roughness can be controlled by appropriate process modifications
- Modeling of optical micro system performance including MEMS non-idealities
- Drive electronics and control software for large numbers of independent high voltage channels available
 - Interconnect scale-up problem currently being addressed by integrated electronics and by via approaches
- Advanced integration schemes involving MEMS in compound semiconductor materials promise the ultimate in monolithic integration: sources, detectors and MEMS on a single chip





MEMS do pop out of plane!

